

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of:

Mikako UJIIE et al.

Appln. No.:

Filed: HERewith

For: A SEMICONDUCTOR DEVICE AND METHOD OF MANUFACTURING THE  
SAME

\* \* \*

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Applicants wish to make of record the documents cited  
in prior Application No. 10/225,163 filed August 22, 2002,  
whether cited by Applicants or by the Patent Office. The  
documents are listed on the attached Form PTO-1449.

Respectfully submitted,

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April 16, 2004

<b>FORM PTO-1449</b>				<b>Atty. Docket No.</b> XA-9730A		<b>Appln. No.</b>	
<b><u>LIST OF DOCUMENTS CITED BY APPLICANT</u></b>				<b>Applicant</b> Mikako UJIIE et al.			
				<b>Filing Date</b> HEREWITH		<b>Group</b>	
<b>U.S. PATENT DOCUMENTS</b>							
<b>Examiner Initial</b>		<b>Document Number</b>	<b>Date</b>	<b>Name</b>	<b>Class</b>	<b>Sub-class</b>	<b>Filing Date</b>
	AA	6,200,121	3/13/01	Tsuruta	425	127	
	AB	2002/0149102	10/02	Hashemi et al.	257	706	
	AC	6,448,507	9/02	Fontecha et al.	174	260	
	AD	5,336,931	8/94	Juskey et al.	257	787	
	AE	2001/0026959	10/01	Jimarez et al.	438	126	
	AF	2002/0084518	7/02	Hasebe et al.	257	676	
	AG	2002/0168798	11/02	Glenn et al.	438	110	
	AH	2003/0042621	3/03	Chen et al.	257	784	
	AI	2002/0125557	9/02	Chen et al.	257	686	
<b>FOREIGN PATENT DOCUMENTS</b>							
<b>Examiner Initial</b>		<b>Document Number</b>	<b>Date</b>	<b>Country</b>	<b>Class</b>	<b>Sub-class</b>	<b>Translation</b>
	AJ	8-181166	7/12/96	JAPAN			abstract
	AK	7-45641	2/14/95	JAPAN			abstract
	AL	8-167678	6/25/96	JAPAN			abstract
	AM	2000-286271	10/13/00	JAPAN			abstract
	AN	2000-12578	1/14/00	JAPAN			abstract
	AO						
<b>OTHER</b> (including author, title, date, pertinent pages, etc.)							
	AP						
	AQ						
	AR						
<b>Examiner</b>				<b>Date Considered</b>			
<b>EXAMINER:</b> Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							